

Microelectronics Technology

ECSE - 2210

Midterm Exam

Solution

Spring Semester 2014

Question 1

(a) Sample absorbs 250 mW power. Light has wavelength of 450 nm.

Absorbed number of photons per unit time =

$$= \frac{P}{h\nu} = \frac{P}{h \frac{c}{\lambda}} = \frac{0.25 \text{ W}}{6.63 \times 10^{-34} \text{ J s} \cdot 3 \times 10^8 \text{ m/s} \cdot 450 \times 10^{-9} \text{ m}}$$

$$= \frac{0.25}{6.63 \times 3} \frac{450}{10^{-34} 10^8} \frac{\text{J}}{\text{J s m}} \frac{\text{s m}}{\text{m}}$$

$$= ~~5.66 \times 10^{17} \frac{1}{\text{s}}~~ \underline{\underline{5.66 \times 10^{17} \frac{1}{\text{s}}}}$$

$$\text{Generation rate} = G = \frac{5.66 \times 10^{17} \text{ s}^{-1}}{10^{-3} \text{ mm}^3} =$$

$$= 5.66 \frac{10^{17}}{10^{-3}} \frac{\text{s}^{-1}}{10^{-3} \text{ cm}^3} = \underline{\underline{5.66 \times 10^{23} \text{ cm}^{-3} \text{ s}^{-1}}}$$

(b) Emitted power

$$P = \frac{E}{t} = 10^{17} \text{ s}^{-1} \times 1 \text{ eV} = \frac{10^{17}}{\text{s}} \cdot 1.6 \times 10^{-19} \text{ J}$$

$$= 1.6 \times 10^{-2} \text{ W} = \underline{\underline{16 \text{ mW}}}$$

$$(c) \text{ Quantum efficiency} = \frac{\text{Emission rate}}{\text{Absorption rate}} =$$
$$= \frac{10^{17} \frac{1}{s}}{5.66 \times 10^{17} \frac{1}{s}} = \underline{\underline{17.7\%}}$$

$$(d) \text{ Power efficiency} = \frac{\text{Emitted power}}{\text{Absorbed power}} =$$
$$\frac{16 \text{ mW}}{250 \text{ mW}} = \underline{\underline{6.4\%}}$$

(e) Non-radiative recombination caused by defects, impurities, or traps (also called "luminescence killers")

Question 2

2. Circle the correct answer:

- (a) For a semiconductor sample with quantum efficiency of 1, the wavelength of the absorbed light must be shorter than the wavelength of the emitted light. T F I
- (b) The Einstein relation suggests that particles that have a high mobility diffuse very little (and vice versa). T F I
- (c) In a constant electric field electrons propagate with a drift velocity that is constant over time. T F I
- (d) Generally, charge carriers diffuse more rapidly at $T = 300$ K than they do at 200 K. T F I
- (e) A silicon (Si) pn junction can be intentionally doped with phosphorus (P) donors, and carbon (C) acceptors. T F I
- (f) The continuity equation expresses the fact that all carriers must be accounted for. T F I

T = True; F = False; I = Impossible to answer with information provided

Remarks

- (a) Required by energy conservation
- (b) $D \propto \mu$
- (c) $v = \mu E$
- (d) Driving force for diffusion is the thermal energy $E_{\text{thermal}} = kT$
- (e) C is not an acceptor in Si
- (f) This is correct.

Question 3

Si sample. $n = 10^{10} \text{ cm}^{-3}$ $E = 100 \text{ V/cm}$

For Si: $n_i = 10^{10} \text{ cm}^{-3}$

$$(a) \quad n p = n_i^2 \quad \Rightarrow \quad p = \frac{n_i^2}{n} = \frac{(10^{10} \text{ cm}^{-3})^2}{10^{10} \text{ cm}^{-3}} \\ = \underline{\underline{10^{10} \text{ cm}^{-3}}}$$

$$(b) \quad \mu_n = 1500 \text{ cm}^2/\text{Vs} \quad \mu_p = 450 \text{ cm}^2/\text{Vs}$$

$$V_{\text{Drift}} = \mu_n E = 1500 \text{ cm}^2/\text{Vs} \cdot 100 \frac{\text{V}}{\text{cm}} = 15 \times 10^4 \frac{\text{cm}}{\text{s}} \\ = \underline{\underline{1500 \frac{\text{m}}{\text{s}}}}$$

$$(c) \quad V_{\text{Drift}} = \mu_p E = 450 \frac{\text{cm}^2}{\text{Vs}} \cdot 100 \frac{\text{V}}{\text{cm}} = \underline{\underline{450 \frac{\text{m}}{\text{s}}}}$$

(d) Electron drift current density

$$J_n = e n v = 1.6 \times 10^{-19} \text{ C} \times 10^{10} \text{ cm}^{-3} \cdot 15 \times 10^4 \frac{\text{cm}}{\text{s}}$$

$$= 24 \times 10^{-5} \frac{\text{C}}{\text{s}} \frac{1}{\text{cm}^2} = 240 \times 10^{-6} \frac{\text{A}}{\text{cm}^2}$$

$$= \underline{\underline{240 \mu\text{A}/\text{cm}^2}}$$

$$\begin{aligned}
 \text{(e)} \quad J_p &= e p v = 1.6 \times 10^{-19} \text{ C} \times 10^{10} \text{ cm}^{-3} \times 4.5 \times 10^4 \\
 \frac{\text{cm}}{\text{s}} &= 7.2 \times 10^{-5} \frac{\text{C cm}^{-3} \text{ cm}}{\text{s}} = 72 \times 10^{-6} \frac{\text{A}}{\text{cm}^2} \\
 &= \underline{\underline{72 \frac{\mu\text{A}}{\text{cm}^2}}}
 \end{aligned}$$

$$\begin{aligned}
 \text{(f)} \quad J_{\text{diffusion}} &= J_{\text{drift}} = \left| -e D_n \frac{dn}{dx} \right| = 240 \frac{\mu\text{A}}{\text{cm}^2} \\
 \Rightarrow \frac{dn}{dx} &= 240 \frac{\mu\text{A}}{\text{cm}^2} \frac{1}{e} \frac{1}{D_n} = \frac{240 \times 10^{-6} \text{ A}}{1.6 \times 10^{-19} \text{ C} \text{ cm}^2} \frac{\text{s}}{39 \text{ cm}^2} \\
 &= \underline{\underline{3.85 \times 10^{13} \frac{1}{\text{cm}^3 \text{ cm}}}}
 \end{aligned}$$

Question 4

Si pn junction. $N_D = 10^{18} \text{ cm}^{-3}$ $N_A = 10^{16} \text{ cm}^{-3}$

(a) Depletion layer thickness

$$\begin{aligned}
 V_{bi} = V_D &= \frac{kT}{e} \ln \frac{n_{n0} p_{p0}}{n_i^2} \\
 &= 26 \text{ mV} \ln \frac{10^{18} \text{ cm}^{-3} 10^{16} \text{ cm}^{-3}}{10^{20} \text{ cm}^{-6}} = 26 \text{ mV} \ln(10^{14}) \\
 &= 838 \text{ mV}
 \end{aligned}$$

$$\begin{aligned}
 W_D &= \sqrt{\frac{2 \epsilon_r \epsilon_0 V_{bi}}{e} \frac{N_D + N_A}{N_D N_A}} = \\
 &= \sqrt{\frac{2 \times 11.9 \times 8.85 \times 10^{-12} \frac{\text{As}}{\text{Vm}} \cdot 0.838 \text{ V}}{1.6 \times 10^{-19} \text{ C}} \frac{1.01 \times 10^{18} \text{ cm}^{-3}}{10^{34} \text{ cm}^{-6}}} \\
 &= \sqrt{111 \times \frac{10^6}{10^{15}} \frac{1}{\text{m}} \text{ cm}^3} = \sqrt{111 \times 10^{-9} \frac{1}{100 \text{ cm}} \text{ cm}^3} \\
 &= \sqrt{11.9 \times 10^{-8} 10^{-2}} \text{ cm} = 3.45 \times 10^{-5} \text{ cm} \\
 &= ~~0.345 \times 10^{-4} \text{ cm}~~ = \underline{\underline{0.345 \mu\text{m}}}
 \end{aligned}$$

- (b)
- (1) Electron drift current
 - (2) Hole drift current
 - (3) Electron diffusion current
 - (4) Hole diffusion current

(c) Shockley equation:

$$J = e \left(\frac{D_p}{L_p} p_{n0} + \frac{D_n}{L_n} n_{p0} \right) (e^{eV/kT} - 1)$$

It is $n_{n0} \gg p_{p0} \Rightarrow n_{p0} \gg p_{n0}$.

\Rightarrow Second summand \Rightarrow First summand

In forward direction, the diffusion current dominates. \Rightarrow Electron diffusion current dominates.

(d) Under equilibrium conditions (i.e. $V=0$), the four currents cancel out.

(e) J_s can be reduced by:

(1) Increasing N_A

(2) Increasing N_D

(3) Increasing E_g (and thus decreasing n_i)